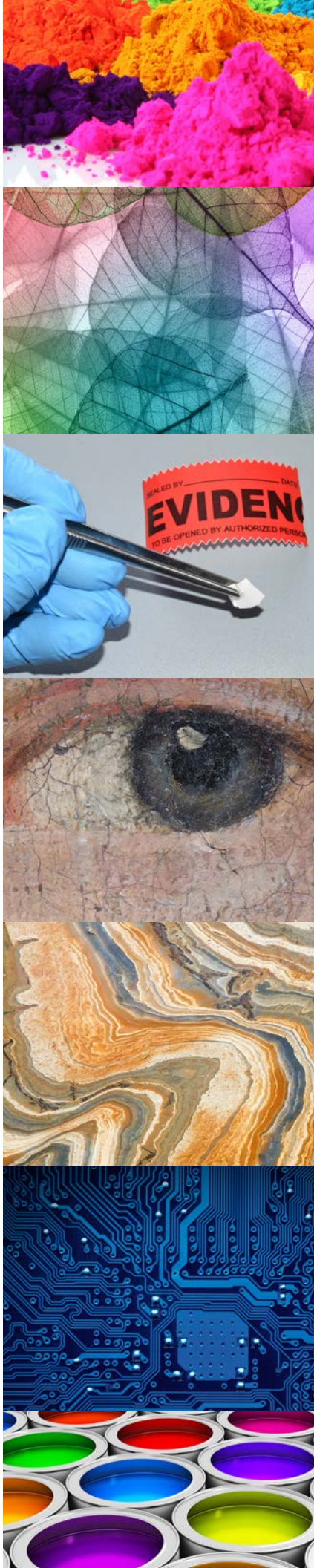
ATLAS M TECHNICAL SPECIFICATIONS

Sample Types	Solids, Liquids, Particles, Powders
Sample Chamber Size	20x18x10in. (508x457x254mm)
Measurement Media	Air, Vacuum, He
Excitation Source Primary Secondary	 50W / 50kV / 1mA 4W-12W / 40kV-60kV / 0.4mA-1mA
Excitation Parameters Target Materials Tube Spot Size Filters	Polycapillary or Aperture Collimation Rh (others available) 50kV, 50W, 1mA (optional 2nd tube) ≥5-1000µm Up to 8
Geometry	Top-down Beam (Perpendicular)
Detector (s) Resolution Active Area	SDD (Si-Pin upon request) 130-145eV 50-150mm^2
Stage	Motorized X,Y,Z (available) 25x25mm up to 320x320mm ranges available
Sample Travel Total Mapping Map Scan Speed Sample Speed	320x320x120mm 220x200mm 1-3ms/pixel up to 300mm/second
Sample View	Three Sample Positioning and Analysis Cameras
Instrument Control	PC; Windows 10 Complete control of parameters, filters, cameras, optical microscopes, sample illumination and positioning, and measurement media
Power	100-240 V, 50/60 Hz
Certifications	CE, RoHS, Radiation
Element Range	Na-U
Dimensions	35x22x22in (890x560x560mm)
Quality and Safety	CE certified RoHS, Radiation < 1 µSv/h





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